S	earch	Notes	

Application/Control No.	Applicant(s)/Patent under Reexamination
09/752,918	LEE ET AL.
Examiner	Art Unit

2667

Afsar M. Qureshi

SEARCHED				
Class	Subclass	Date	Examiner	
370	310.2	5/11/2005	AQ	
	328			
	338			
	389			
	395.52			
	395.62		,	
	395.71			
	401			
	535			

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
370	310.2	5/11/2005	AQ
	328		
	389		
370	/535		

SEARCH NOT (INCLUDING SEARCH	ES STRATEGY)
	DATE	EXMR
EAST/WEST	5/11/2005	AQ
IEEE/ACM/IBM		
IP.Com / DERWENT		·